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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/543,111	CAWTHON, RICHARD	
Examiner	Art Unit	
Young J. Kim	1637	

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INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	8/17/2007	YJK
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